

<b>Notice of References Cited</b>	Application/Control No. 10/536,808		Applicant(s)/Patent Under Reexamination KIRSCH ET AL.	
	Examiner Shean C. Wu		Art Unit 1756	Page 1 of 1

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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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